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L	APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
	10/750,845	01/05/2004	Sung-Chul Kang	YOM-0205	3873
	23413 7	590 06/27/2006		EXAM	INER
	CANTOR CO 55 GRIFFIN R	OLBURN, LLP OAD SOUTH		сни, јо	HN S Y
	BLOOMFIELI	O, CT 06002		ART UNIT	PAPER NUMBER
				1752	
				DATE MAIL ED: 06/27/2004	•

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)
	10/750,845	KANG ET AL.
Office Action Summary	Examiner	Art Unit
	John S. Chu	1752
The MAILING DATE of this communication apperiod for Reply	pears on the cover sheet with the c	orrespondence address
A SHORTENED STATUTORY PERIOD FOR REPL WHICHEVER IS LONGER, FROM THE MAILING D - Extensions of time may be available under the provisions of 37 CFR 1. after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailin earned patent term adjustment. See 37 CFR 1.704(b).	PATE OF THIS COMMUNICATION 136(a). In no event, however, may a reply be tin will apply and will expire SIX (6) MONTHS from the cause the application to become ARANDONE	N. nely filed the mailing date of this communication. D. (35 U.S.C. 6 133)
Status		
1) Responsive to communication(s) filed on <u>02 J</u>	une 2006.	
	s action is non-final.	
3) Since this application is in condition for allowa	nce except for formal matters, pro	secution as to the merits is
closed in accordance with the practice under I	Ex parte Quayle, 1935 C.D. 11, 45	53 O.G. 213.
Disposition of Claims		
4) Claim(s) 11-14 and 16-20 is/are pending in the 4a) Of the above claim(s) is/are withdra 5) Claim(s) is/are allowed. 6) Claim(s) 11-14 and 16-20 is/are rejected. 7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and/or	wn from consideration.	
Application Papers		
9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) acc Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Examine 11.	epted or b) objected to by the for drawing(s) be held in abeyance. See tion is required if the drawing(s) is obj	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).
Priority under 35 U.S.C. § 119		
12) Acknowledgment is made of a claim for foreigna) All b) Some * c) None of:	priority under 35 U.S.C. § 119(a)	-(d) or (f).
1.⊠ Certified copies of the priority document	ts have been received	
2. Certified copies of the priority document		on No
Copies of the certified copies of the prio application from the International Bureat * See the attached detailed Office action for a list	rity documents have been receive u (PCT Rule 17.2(a)).	ed in this National Stage
Attachment(s)		
1) Notice of References Cited (PTO-892)	4) Interview Summary	
 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date 	Paper No(s)/Mail Da 5) Notice of Informal Pa 6) Other:	te atent Application (PTO-152)
S. Patent and Trademark Office PTOL-326 (Rev. 7-05) Office Ad	ction Summary Par	rt of Paper No./Mail Date 20060621

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DETAILED ACTION

This Office action is in response to the amendment filed June 2, 2006.

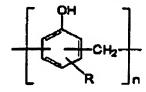
Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 11-14 and 16-20 are rejected under 35 U.S.C. 103(a) as being unpatentable over JEFFRIES, III et al (5,346,799) or EBERSOLE (5,324,620) in view of KODAMA et al (5,853,949) SHERIFF et al (6,117,610) and GRACIA et al (6,232,031 B1).

The claimed invention has been recited hereafter:

- 11. (Currently Amended) A method for applying a photoresist composition to an MMN head coater, wherein the photoresist composition comprises:
- (a) 5 wt% to 30 wt% of a polymer resin represented by the following Chemical Formula 1;
 - (b) 2 wt% to 10 wt% of a diazide photoactive compound;
 - (c) 50 wt% to 90 wt% of an organic solvent; and
 - (d) 500 to 4000 ppm of a Si based surfactant:

Chemical Formula 1



wherein R is C₁ to C₄ alkyl, and n is an integer of 15 to 10,000, and wherein the Si-hased surfactant is a polyoxyalkylene dimethylpolysiloxane copplymer compound.

and is included by reference wherein claim 6 is further drawn to the addition of a crosslinking agent is shown below:

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16. (withdrawn) The method of Claim 11,

wherein the composition further comprises one or more nitrogen-containing crosslinking agents selected from the group consisting of a condensation product of urea and formaldehyde, a condensation product of melamine and formaldehyde, a methylol urea alkylether, and a methylol melamine alkylether.

Each of JEFFRIES, III et al, or EBERSOLE recite a photoresist composition comprising a S-based surfactant in a composition comprising a novolak resin and a quinonediazide compound. Said references fail to teach the use of a crosslinking agent in the photoresist composition as currently recited in claim 6.

KODAMA et al '949 discloses a positive photoresist composition comprising a novolak resin and a quinonediazide compound with the addition of a polyphenol compound, see <u>column 6, lines 32 – column 7, line 60</u> for the alkali-soluble resin and photosensitive compound.

Applicants are directed to <u>column 11, lines 46-51</u> wherein KODAMA et al teaches the use of surfactants being Si-based. In fact the same surfactants as disclosed in JEFFRIES, III et al and EBERSOLE are disclosed here in KODAMA et al, see the surfactant trade name of FLORAD FC-430 in <u>column 11, line 46</u>.

The primary disclosure which the examiner relies on is found in <u>column 12</u>, lines 40-56 wherein KODAMA et al discloses the suitable use of crosslinking agents which serve to improve the dry etching resistance, improve sensitivity and heat resistance, yet not alter the positive working property of the photoresist composition. Specific crosslinking agents include

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melamine-formaldehyde and others like benzoguanamine and glycouril-formaldehyde. Thus the skilled artisan is motivated to use such components to improve the photoresist image that is formed.

Each of SHERIFF et al and GRACIA et al are cited of interest with respect to the use of polyether modified dimethylpolysiloxane copolymer surfactants. The <u>Examples 3-6</u> in SHERIFF et al disclose the following attached:

EXAMPLES 3-6

Four imaging compositions and plates of the present invention were prepared using the following components:

COMPONENT	Example 3 (grams)	Example 4 (grams)	Example 5 (grams)	Example 6 (grams)
Cresol-formaldehyde novolac resin	4.620	4.620	4.620	4.620
2,4-Bis(2-diazo-1,2-dihydro-1-oxo-5-naphthalenesulfonyloxy) benzo-phenone	1.154	1.154	1.154	1.154
Carbon black	0.108	0.217	0.434	0.868
1-Methoxy-2-propanol solvent	88.118	88.009	87.792	87.358
Acetone	5.881	5.881	5.881	5.881
CG-21-1005	0.108	0.108	0.108	0.108
BYK-307	0.011	0.011	0.011	0.011

CG 21-1005 is a dye available from Ciba-Geigy.

BYK-307 is a polyether-modified polydimethylsiloxane available from BYK-Chemie.

wherein BYK-307 is a surfactant as claimed in claim 11.

GRACIA et al likewise discloses the use of BYK 344 surfactant in Examples 1-4 in a composition with a quinone diazide compound and a novolak resin. Here the use of a polyoxyalkylene dimethylpolysiloxane copolymer surfactant is taught in a composition for photolithographic compositions comprising a diazide compound a phenol novolak resin and a

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solvent. BYK 333 and BYK 344 are attached with their product descriptions from the BYK-Chemie product list.

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It would have been *prima facie* obvious to one of ordinary skill in the art of positive photoresist compositions to add a crosslinking agent, such as melamine-formaldehyde into the photoresist composition of JEFFRIES, III et al or EBERSOLE as an agent to improve dry etching resistance, and heat resistance and reasonably expect same or similar results as disclosed in JEFFRIES, III et al or EBERSOLE for high thermal resistance and low scumming upon development.

It also would have been *prima facie* obvious to one of ordinary skill in the art of photolithographic compositions and coating methods to add the known surfactants as disclosed in SHERIFF et al and GRACIA et al into the compositions of JEFFRIES, III et al, EBERSOLE and reasonably expect same or similar results with respect to having compositions with high thermal resistance.

The argument by applicant have been carefully considered, however it is believed that a prima facie case of obviousness is present wherein the claimed amounts of the surfactant is actually disclosed by SHERIFF et al and GRACIA et al to be conventional ranges wherein GRACIA et al discloses his surfactant to be in an amount of 0.08% as seen in the following table in Example 1:

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EXAMPLE 1

An 830 nm laser plate coating was prepared with an absorbing dye to diazonaphthoquinone weight ratio of 3:1 using the following formulation:

	weight A
Arcosoly PM solvent	59.927
Dimethyl formamide solvent	9.244
Ethanol solvent	22.829
KR 100 cresol formaldehyde resin	7.402
PS 105 diazonaphthoquinone sensitizer	0.185
830A infra-red absorbing dye	0.185
KR 700 coloring dye	0.148
BYK 344 surfactant	0.080

Note: PS 105 diazonaphthoquinone sensitizer is 33% diazonaphthoquinone and 67% phenolic resin.

The coating was applied to an aluminum substrate that was previously brush grained, anodized and silicated. The coat weight was 190 mg/ft². After coating, the plate was dried at 90° C. for four minutes. Next the plate was placed in a Creo Trendsetter imager equipped with a 20 watt 830 nm laser. The plate was imaged at a drum speed of 180 RPM and a laser power setting of 10 watts. On exiting the imager, the imaged plate was placed in a plate processor containing an alkaline developer. The processing speed was 4 ft/min with the following developer formulation:

Examples 2-4 also use the surfactant in an amount of 0.08% which falls in the claimed range of 500 to 4000 ppm.

The rejection is repeated and made final.

3. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

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4. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Examiner Chu whose telephone number is (571) 272-1329. The

examiner can normally be reached on Monday - Friday from 9:30 am to 6:00 pm.

If attempts to reach the Examiner by telephone are unsuccessful, the Examiner's

supervisor, Cynthia Kelly, can be reached on (571) 272-1526

The fax phone number for the USPTO is (571) 273-8300.

Information regarding the status of an application may be obtained from the Patent

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system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR

system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

phn S. Chu

Primary Examiner, Group 1700

J.Chu June 21, 2006